

2016 IEEE International Test Conference (ITC 2016)

**Fort Worth, Texas, USA
15 – 17 November 2016**



IEEE Catalog Number: CFP16ITC-POD
ISBN: 978-1-4673-8774-3

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IEEE Catalog Number:	CFP16ITC-POD
ISBN (Print-On-Demand):	978-1-4673-8774-3
ISBN (Online):	978-1-4673-8773-6
ISSN:	1089-3539

Additional Copies of This Publication Are Available From:

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